

1765

Notice of References Cited

U.S. PATENT DOCUMENTS

Lynette T. Umez-Eronini

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3964957	06-1974	Walsh	156/345
	В	US-5340437	08-1994	Erk et al.	156/639
	С	US-			
	D	US-			
	E	US-			
Ī	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
Ī	J	US-			
	K	US-			
	L	US-			
\exists	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
,	U	Takeshi et al., Method and Apparatus for Evaluating Semiconductor Substrate, May 2, 1997, (Electronic English translation of JP 9115977A2 by Japanese Patent Office, 18 pages.
	٧	
	w	
	х	

*A copy of this reference is not being furnished with this Office action (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign

Page 1 of 1